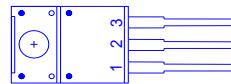
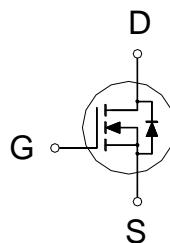


**NIKO-SEM**
**N-Channel Enhancement Mode  
Field Effect Transistor**
**P0470ETF****TO-220F**

Halogen-Free &amp; Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
700V	2.8Ω	4A



1. GATE
2. DRAIN
3. SOURCE

**ABSOLUTE MAXIMUM RATINGS( $T_A=25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	$V_{DS}$	700	V
Gate-Source Voltage	$V_{GS}$	$\pm 30$	V
Continuous Drain Current <sup>2</sup>	$I_D$	4	A
		2.6	
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	16	
Avalanche Current <sup>3</sup>	$I_{AS}$	2	
Avalanche Energy <sup>3</sup>	$E_{AS}$	20	mJ
Power Dissipation	$P_D$	54	W
		22	
Operating Junction & Storage Temperature Range	$T_j, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		2.3	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	°C / W

<sup>1</sup>Pulse width limited by maximum junction temperature.<sup>2</sup>Ensure that the channel temperature does not exceed 150°C.<sup>3</sup> $V_{DD} = 50\text{V}$ ,  $L = 10\text{mH}$ , starting  $T_J = 25^\circ\text{C}$ .**ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	700			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	2	3	4	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0\text{V}, V_{GS} = \pm 30\text{V}$			$\pm 100$	nA

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Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 700V, V_{GS} = 0V, T_C = 25^\circ C$			1	$\mu A$
		$V_{DS} = 560V, V_{GS} = 0V, T_C = 100^\circ C$			10	
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 2A$		2.2	2.8	$\Omega$
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 10V, I_D = 2A$		7.7		S
<b>DYNAMIC</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		661		$pF$
Output Capacitance	$C_{oss}$			63		
Reverse Transfer Capacitance	$C_{rss}$			8		
Total Gate Charge <sup>2</sup>	$Q_g$	$V_{DD} = 560V, I_D = 4A, V_{GS} = 10V$		15		$nC$
Gate-Source Charge <sup>2</sup>	$Q_{gs}$			2.9		
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$			5		
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$	$V_{DD} = 350V, I_D = 4A, R_G = 6\Omega$		37		$nS$
Rise Time <sup>2</sup>	$t_r$			13.5		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$			17		
Fall Time <sup>2</sup>	$t_f$			12.3		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25^\circ C</math>)</b>						
Continuous Current <sup>3</sup>	$I_S$				4	A
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = 4A, V_{GS} = 0V$			1	V
Reverse Recovery Time	$t_{rr}$	$I_F = 4A, dI_F/dt = 100A/\mu S$		354		$nS$
Reverse Recovery Charge	$Q_{rr}$			2.4		$uC$

<sup>1</sup>Pulse test : Pulse Width  $\leq 380 \mu sec$ , Duty Cycle  $\leq 2\%$ .

<sup>2</sup>Independent of operating temperature.

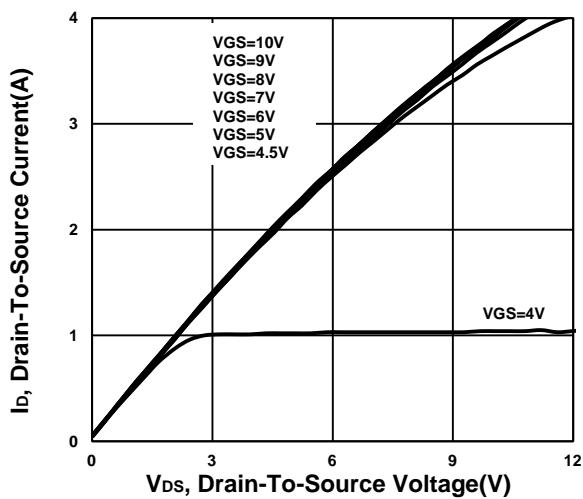
<sup>3</sup>Pulse width limited by maximum junction temperature.

**NIKO-SEM**

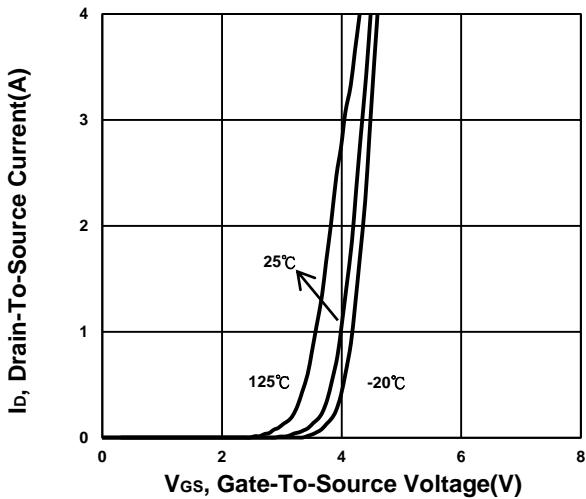
**N-Channel Enhancement Mode  
Field Effect Transistor**

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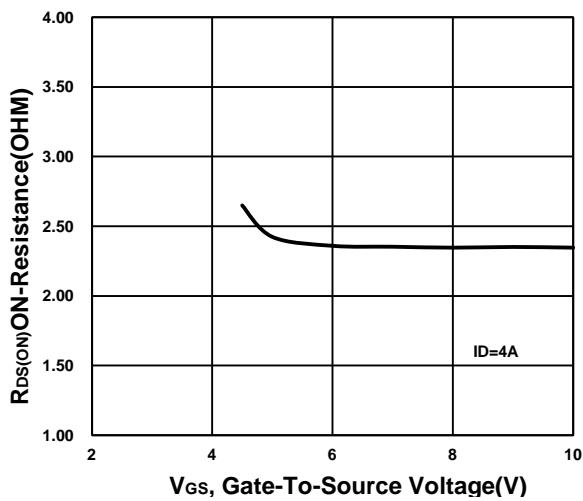
**Output Characteristics**



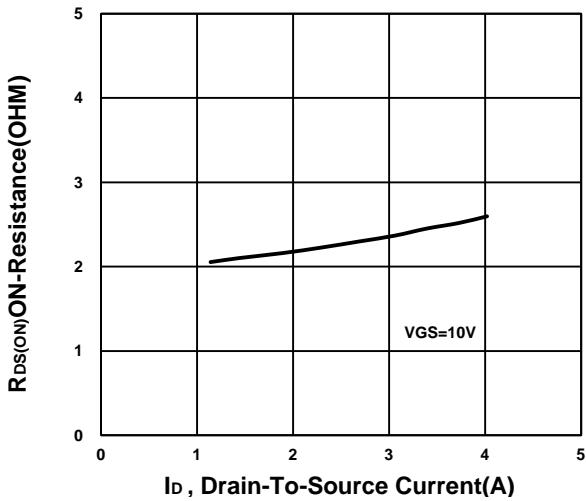
**Transfer Characteristics**



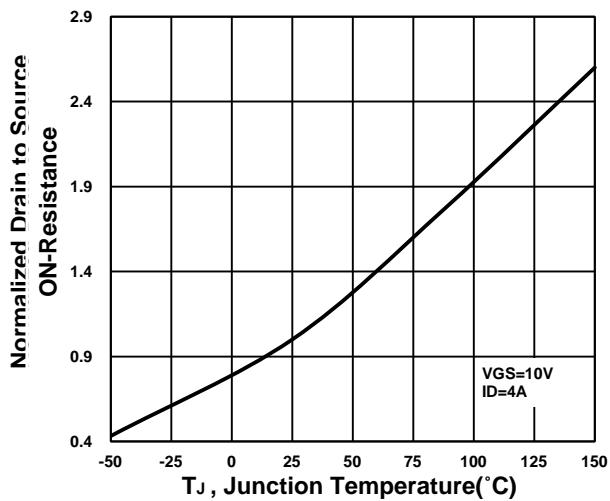
**On-Resistance VS Gate-To-Source**



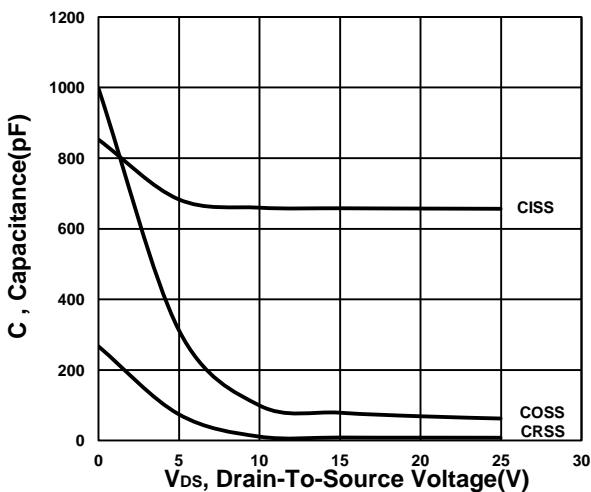
**On-Resistance VS Drain Current**



**On-Resistance VS Temperature**



**Capacitance Characteristic**

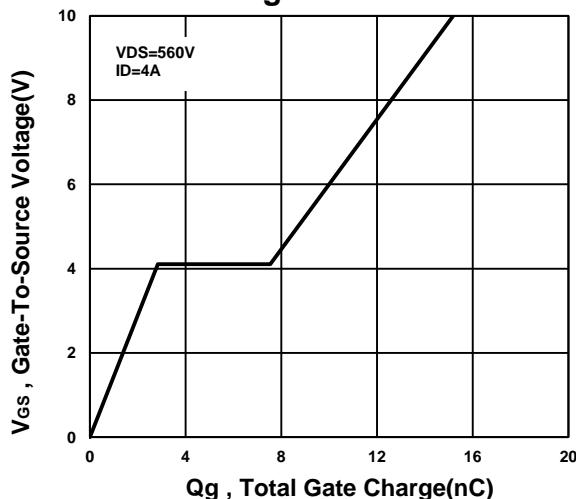


**NIKO-SEM**

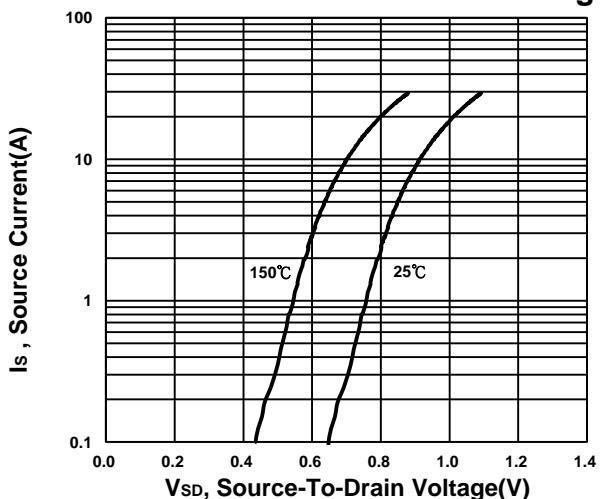
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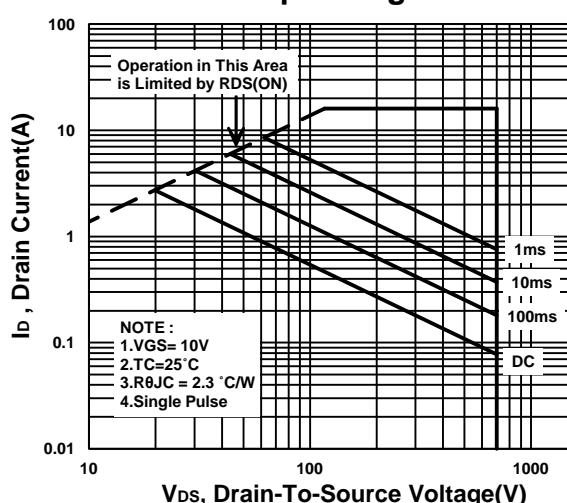
**Gate charge Characteristics**



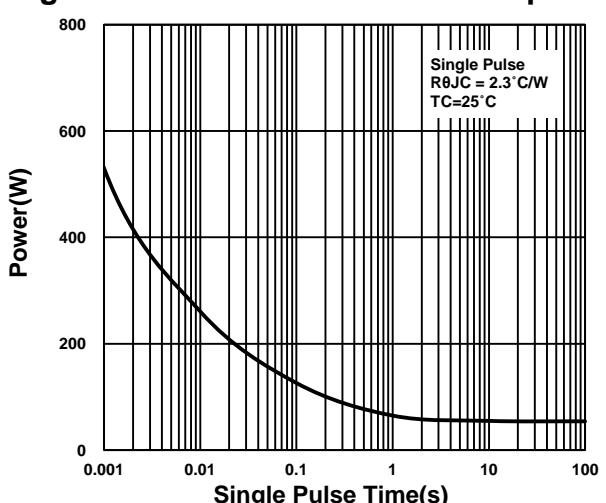
**Source-Drain Diode Forward Voltage**



**Safe Operating Area**



**Single Pulse Maximum Power Dissipation**



**Transient Thermal Response Curve**

